DCN Name Is a sec	2016000000		DON Dates	0/10/2016	
PCN Number:	20160808000		PCN Date:	8/19/2016	
Title: Datasheet for	TMDS181				
Customer Contact:	PCN Manager		Dep	Quality	
customer contact.	T CIT Mariager		Бер	Services	
Change Type:					
Assembly Site		Design		Wafer Bump Site	
Assembly Process		Data Sheet		Wafer Bump Material	
Assembly Materials		Part number cha	ange	Wafer Bump Process	
Mechanical Specification		Test Site		Wafer Fab Site	
Packing/Shipping/Labeling		Test Process		Wafer Fab Materials	
				Wafer Fab Process	
I					
Description of Change		ification Deta	u113		
Description of Change Texas Instruments Inco		ouncing an inform	nation only not	ification	
rexas instruments inco	i porateu is aiiii	ouncing an inion	mation only not	ilication.	
The product datasheet(s) is being updated as summarized below. The following change history provides further details.					
Mr. There are					
TEXAS INSTRUMENTS				TMDS181, TMDS181I	
INSTRUMENTS			SLASE75B -	AUGUST 2015-REVISED APRIL 2016	
Changes from Revision A (O	ctober 2015) to Rev	ision B	·	Page	
Added V., "Low-level input	voltage at HPD_OF"	to the Pecommended O	nerating Conditions	7	
				perating Conditions 7	
Deleted the VDD_ramp and VCC_ramp MIN values in Power-Up and Operation Timing Requirements					
Changed text "address 22h (see Figure 31) through the I2C interface." To: "address 0Bh through the I2C interface." in DDC Functional Description.					
·					
TEXAS TMDS181, TMDS181I SLASE75C –AUGUST 2015–REVISED JULY 2016					
Changes from Revision B (A	April 2016) to Revisi	on C		Page	
Recommended Operating	Conditions. Changed	I the CONTROL PINS s	ection	7	
 Recommended Operating Conditions, Changed the CONTROL PINS section					
223, 13, 111 2, and 1110	<u> </u>	onoc, changes the DDC	7442 1 0 0004011		
The datasheet number	will be changing	g.			
Device Family		ge From:	Chang	іе То:	
TMDS181	SLASI		SLAS		
These changes may be reviewed at the datasheet links provided. http://www.ti.com/product/TMDS181					
nttp.//www.ti.com/product/ inipotot					
Reason for Change:					
To more accurately reflect device characteristics.					
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive /					
negative):					
No anticipated impact.		cation change an	nouncement on	ly. There are no	
changes to the actual device.					

Changes to product identification resulting from this PCN:					
None.					
Product Affected:					
TMDS181IRGZR	TMDS181IRGZT	TMDS181RGZR	TMDS181RGZT		

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
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